## Applicant(s)/Patent Under Application/Control No. Reexamination 10/643,102 KRIER ET AL. Notice of References Cited Examiner Art Unit Page 1 of 1 2821 Minh D. A **U.S. PATENT DOCUMENTS** Date **Document Number** Classification Name Country Code-Number-Kind Code MM-YYYY US-2004/0169614 09-2004 343/803 Desclos et al. Α 07-2003 US-6,597,318 Parsche et al. 343/700MS В US-GB 2387486 10-2003 343/700ms С Jong Cheo Yoon US-D US-Ε US-F US-G US-Н US-US-J US-Κ US-US-M FOREIGN PATENT DOCUMENTS **Document Number** Date Country Name Classification Country Code-Number-Kind Code MM-YYYY Ν 0 Ρ Q R S Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U W

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